



Docket No.: M4065.0215/P215  
(PATENT)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of:  
Eugene A. DeLaRosa et al.

Application No.: 09/516,581

Confirmation No.: 3124

Filed: March 1, 2000

Art Unit: 2621

For: METHOD FOR MEASURING  
REGISTRATION OF OVERLAPPING  
MATERIAL LAYERS OF AN INTEGRATED  
CIRCUIT

Examiner: B. P. Werner

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*12/29/05*

**AMENDMENT AFTER FINAL ACTION (37 C.F.R. SECTION 1.116)**

MS AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

**INTRODUCTORY COMMENTS**

In response to the Office Action dated September 15, 2005, finally rejecting claims 1, 3-14, 16-27, and 29-39, please amend the above-identified U.S. patent application as follows:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks** begin on page 9 of this paper.